REMARKS

This application contains claims 1 through 18. Claims 17 and 18 are newly added.

The present application was originally drafted in German, and then translated into English. In the present amendment, Applicants amended the claims to remove multiple dependencies, to conform to US drafting style, and to delete extraneous language. Applicants have not limited the scope of any term in any claim, and thus, Applicants respectfully submit that the doctrine of equivalents is available for all terms of all of the claims. Favorable consideration is respectfully urged.

Respectfully submitted,

Charles N.J. Ruggiero, Esq.

Reg. No. 28,468

Attorney for the Applicants

Ohlandt, Greeley, Ruggiero & Perle, L.L.P.

One Landmark Square, 10th Floor

Stamford, CT 06901-2682

Tel: 203-327-4500 Fax: 203-327-6401

IN THE CLAIMS

- 1. (Amended) Illumination An illumination system, particularly for lithography with wavelengths of ≤193 nm comprising:
 - 1.1 a first optical element, which is divided into first raster elements and lies in a first plane, whereby
 - wherein said first plane defines an x-direction and an a y-direction, whereby
 - 1.2 the images of the first raster elements superimpose in an object plane of the illumination system and
 - 1.4 the wherein said first raster elements each have an x-direction and a y-direction with a-an aspect ratio, and

characterized in that

- 1.5 wherein at least two of said first raster elements each have a aspect ratio ratios of different magnitude.
- 2. (Amended) <u>The illumination Illumination</u> system according to claim 1, <u>further characterized in that</u>

the illumination system comprises further comprising a second optical element, which is divided into second raster elements, whereby

wherein a second raster element is assigned to a first raster element, and whereby wherein at least one second raster element has an anamorphotic optical effect.

- 3. (Amended) The illumination Hlumination system according to claim 2, further characterized in that wherein the illumination system defines a field with a field aspect ratio,
- wherein said field is illuminated in the an object plane of the illumination system, and
- wherein at least some of the said second raster elements have an anamorphotic optical effect, which is selected such that the an aspect ratio of the images of the said first raster elements is substantially the same in the said object plane, independent of the said aspect ratio of the said first raster elements.

4. (Amended) The illumination Illumination system according to one of claims 1 to 3claim 1,

further characterized in thatwherein

at least one of the <u>said</u> at least two first raster elements with aspect ratios of different magnitude has an anamorphotic optical effect.

5. (Amended) <u>The illumination Illumination</u> system according to one of claims 1 to 3 claim 1,

further characterized in that wherein

the <u>said</u> at least two first raster elements with aspect ratios of different magnitude have an isotropic optical effect.

6. (Amended) The illumination Illumination system according to claim 5, further characterized in that wherein the said first raster elements have an isotropic optical effect.

7. (Amended) The illumination Illumination system according to one of claims 1 to 5claim 1,

further characterized in that wherein

those said first raster elements that have an anamorphotic optical effect are of a shape selected from the group consisting of cylinders and/orand toroids.

8. (Amended) The illumination Illumination system according to one of claims 1-to 7-claim 2,

further characterized in that wherein

those <u>said</u> second raster elements that have an anamorphotic optical effect are <u>of a</u> shape selected from the group consisting of cylinders and/or and toroids.

9. (Amended) The illumination Illumination system according to one of claims 1 to 8claim 1,

further characterized in that wherein

all of the said first raster elements are completely illuminated in the said first plane.

10. (Amended) The illumination Illumination system according to one of claims 1 to 9claim 1,

further characterized in that

the illumination system has further comprising a collector unit, which illuminates the said first plane with the said first raster elements.

11. (Amended) The illumination Illumination system according to one of claims 1 to 10claim 1,

further characterized in that

the illumination system has further comprising at least one field mirror.

12. (Amended) <u>The illumination Illumination</u>-system according to claim <u>112</u>, <u>further comprising at least one field mirror</u>,

further characterized in that wherein

the <u>said</u> second raster elements and the <u>said</u> at least one field mirror image the <u>said</u> assigned first raster elements in the <u>an</u> object plane of the illumination system.

13. (Amended) <u>The illumination Illumination</u> system according to one of claims 1-12claim 1,

further characterized in that wherein

the said first raster elements are rectangular.

14. (Amended) <u>The illumination Illumination</u> system according to one of claims 1-13claim 1,

further characterized in that wherein the illumination system defines

the <u>a</u> field to be illuminated in the <u>an</u> object plane of the illumination system, and wherein said field represents a segment of a ring field.

- 15. (Amended) Projection A projection exposure system for microlithography with , comprising:
 - 15.1 aan illumination system according to one of claims 1 to 14claim 1 with an exit pupil (112), which partially collects the an emission produced by a light source (100) and further guides it to illuminate a field in the an object plane of the Illumination illumination system;
 - 15.2 a pattern-bearing mask, which lies in the said object plane (114) of the Illumination system;
 - 15.3-a projection device, particularly a projection objective (126) with an entrance pupil, which coincides with the an exit pupil-(112) of the Illumination illumination system, whereby this wherein said projection objective device images the a lighted portion of the said pattern-bearing mask in an image field of the said projection device; and
 - 15.4 a light-sensitive substrate (124), which lies in the <u>a</u> plane of the <u>said</u> image field of the projection device.
- 16. (Amended) Method A method for producing microelectronic microelectronic components, particularly semiconductor chips with a comprising using the projection exposure system according to claim 15.

Claims 17 and 18 are newly added.